

Process Definition

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Metrology Interoperability Summit

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Lack of complete product definitions

Solution	Evaluate GD&T in AP203 2nd Edition and/or Derivates Solutions
Priority	Highest - Showstopper
Timeframe	Start today
Dependencies	Get buy-in from CAD vendors
Benefit	<p>Match equipment to manufacturing requirements.</p> <p>Enable production process optimization.</p> <p>Reduce measurement planning time by 50%.</p> <p>Significant improvement of machine utilization.</p> <p>Eliminate duplication & errors from reentering data.</p> <p>Eliminate rework due to incorrect tolerance entry.</p> <p>Check for completeness of product definition.</p> <p>Enable off-line vision inspection process development.</p>

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Lack of resource definition

Solution	<p>Assess various measuring system capabilities & resource configuration information</p> <ul style="list-style-type: none">■ ASME B5.59 ,■ DMIS machine configuration,■ I++/Renishaw XML machine configuration work,■ ISO 10360-1 Machine type and definitions <p>Collate various resource equipment standards to revise standards</p>
Priority	High
Timeframe	
Dependencies	Need better sensor model for plug and play
Benefit	<p>Allow you to optimize your capital investment</p> <p>Enterprise wide measurement resource planning,</p>
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No standard for measurement knowledge

Solution	Define extensible interface standard
Priority	High
Duration	3-7 years
Timeframe	Start today
Dependencies	Resource definitions
Metric	Knowledge will be captured and shared with your suppliers, unified best practices for your business
Benefit	Documenting corporate practices, reduce part programming time, improve the measurement process, adds consistency to the process across enterprise, works for customers and suppliers, better control of measurement costs

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DMIS support all measuring devices

Solution	Verify DMIS against various measuring devices
Priority	Medium
Timeframe	3 year startup then ongoing
Dependencies	None
Benefit	Use same software to produce programs for different measurement devices (maybe). Reduced training costs.

Macro-to-multiple-micro planning interface is not well defined

Solution	Define content of the interface
Action	Evaluate candidate solutions, if it is DMIS. If not create one or enhance DMIS.
Priority	Medium
Barriers	Lack of knowledge, education. Cooperation with CNC suppliers and vendors.
Dependencies	Solve GD&T issue for automation
Benefit	Same as microplanning benefits + ability to manufacturing verification. Adaptive manufacturing, with in-process changes.